

Notice of References Cited	Application/Control No. 09/683,020	Applicant(s)/Patent Under Reexamination GOEBEL, KAI FRANK	
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	V	"Design-Ease Software Version 6 User's Guide" Stat-Ease Inc. Copyright 2000
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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